## Restraining the polarization increase of Ni-rich and low-Co cathodes

## upon cycling by Al-doping

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Fig. S1 Cross-sectional elemental mapping of NCMA92.



**Fig. S2** The Rietveld refinement of X-ray diffraction patterns: (a) NCM 94, (b) NCMA 92. Corresponding refined atom occupation: (c) NCM94 and (d) NCMA 92.



Fig. S3 Differential capacity profiles (dQ  $dV^{-1}$ ) from 1<sup>st</sup> to 6<sup>th</sup> cycle at 0.1C rate: (a) NCM 94 and (b) NCMA 92.



Fig. S4 Discharge median voltage as a function of cycle number during cycling at 0.5C.



Fig. S5 Cyclic voltammogram of (a) NCM 94 and (b) NCMA92 in the potential range of 2.7-4.3 V versus Li<sup>+</sup>/Li at 10  $\mu$ V/s, which are performed before and after 50 cycles (at a 0.5C rate).



**Fig. S6** GITT test results (line chart) during (a) the first charging and (b) the second charging and the corresponding voltage drop at rest (dot chart). Galvanostatic current pulses are applied with magnitudes of 20 mA  $g^{-1}$  for 30 min, followed by a 3h rest period.



**Fig. S7** Nyquist plots showing the impedance evolution during the charging process of the first cycle: (a) NCM 94 and (b) NCMA 92. (c) The corresponding fitting results of  $R_{et}$ .



**Fig. S8** The fitting results of  $R_f$  during charging of (a) the first cycle and (b) the second cycle. The corresponding Nyquist plots are shown in Fig. S5 and Fig. 8.

**Table S1.** Chemical compositions of Ni, Co, Mn, and Al for the NCM94 and NCMA92 cathodes measured by ICP-OES.

Sample	Value	Atomic Ratio					
		Ni	Co	Mn	Al		
NCM94	Design	0.94	0.03	0.03	0		
	Measurement	0.939	0.029	0.032	0		
NCMA92	Design	0.92	0.03	0.03	0.02		
	Measurement	0.919	0.030	0.030	0.021		

**Table S2.** Lattice parameters of the NCM94 and NCMA92 cathodes are obtained through GSAS.

Samples	R <sub>wp</sub>	R <sub>p</sub>	a (Å)	c (Å)	V (Å <sup>3</sup> )	Ni in Li site
NCM94	2.75%	1.72%	2.8760	14.1891	101.636	2.54%
NCMA92	3.05%	1.93%	2.8746	14.1994	101.615	2.39%

Table S3. The surface-film resistances  $(R_{sf})$  and the charge-transfer resistance  $(R_{ct})$  from EIS tests.

Sample	Resistance	1st	25th	50th	75th	100th
NCM94	$R_{sf}^{}/\Omega$	28.30	10.8	13.86	11.63	11.35
	$R_{ct}^{}/\Omega$	8.10	22.82	114.20	170.60	255.80
NCMA92	$R_{sf}^{}/\Omega$	23.92	5 .67	6.635	6.78	5.11
	$R_{ct}^{}/\Omega$	1.33	12.62	11.00	27.25	47.97